

10/667,879

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4007	burn-in test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 17:58
L2	784394	register\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 17:59
L3	63	I1 same I2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 17:59
L4	7658	combinational logic\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 17:59
L6	1	burn-in configuration register\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:01
L8	242	("IC Die identification" or (id)) same (scan data)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:01
L9	1	I3 and I4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:41
L11	3	I4 and I8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:26

L12	1	l11 and l1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:04
L15	1	(ID scan out signal\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:06
L16	72	memory built-in self-test signal\$1 or (BIST signal\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:29
L17	1	l11 and l16	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:29
L18	3	l16 and l1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:40
L19	1	l18 and l8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:29
L20	3342	scan chain\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:30
L21	11716	burn-in	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:30

L22	119	I20 and I21	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:30
L23	52	I22 and I1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:30
L24	33	I23 and (I2 or I4 or I8 or I16)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:30
L25	60	scan chain signal\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:31
L26	4	I24 and I25	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:38
L27	58109	"exclusive OR" or "XOR"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:31
L28	1	I26 and I27	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:38
L29	9	I24 and I27	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:02

L30	31781	monitor\$3 with output signal\$1 or monitored output signal\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:33
L31	2	I29 and I30	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:36
L32	8208	714/7726 or 714/727 or 714/724 or 714/733 or 714/734 or 714/819 or 324/? or 702/? or 365/202 or 714/738	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:35
L33	1	I29 and I32	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 18:35
L34	1	"DIE ID SCOUT ENABLE"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:03
L35	1	"MBIST FAIL ENABLE"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:03
L36	1	"SCOUT CHAIN ENABLE"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:03
L37	1	L34 AND L35 AND L36	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:04

L38	1	(burn-in configuration register\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:05
L39	7	(burn-in register\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:05
L40	1	"DIE ID scan out"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:05
L42	1	"ID scan out"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:07
L43	2358	"scan out"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:06
L46	5	I29 and I43	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:08
L47	292	monitor\$3 and (scan automatic test pattern generation or (ATPG))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:09
L48	1	I46 and I47	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:09

L49	72	memory built-in self-test pattern\$1 or (BIST pattern\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:10
L50	6	I47 and I49	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:12
L54	1	generat\$3 and (monitored IC output signal\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2006/01/21 19:12